

31031 U.S. PTO  
10/0169  
12/13/01

5c/120

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**U.S. UTILITY Patent Application**

**PATENT NUMBER and  
ISSUE DATE**

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10016943	12/13/2001	256 <sup>356</sup>	516	2878	TURNER

**\*\*APPLICANTS:** Rovira Pablo;

**\*\*CONTINUING DATA VERIFIED:**

**\*\* FOREIGN APPLICATIONS VERIFIED:**

PG-PUB DO NOT PUBLISH ☒

RESCIND ☐

Foreign priority claimed ☐ yes ☐ no

35 USC 119 conditions met ☐ yes ☐ no

Verified and Acknowledged Examiner's initials

ATTORNEY DOCKET NO

M-12350 US

**TITLE :** Optical metrology system with combined interferometer and ellipsometer

U.S. DEPT. OF COMM./PAT. & TM.-PTO-436L (Rev. 12-94)

NOTICE OF ALLOWANCE MAILED		Assistant Examiner	CLAIMS ALLOWED	
			Total Claims	Print Claim for O.G.
ISSUE FEE		Primary Examiner	DRAWING	
Amount Due	Date Paid		Sheets Drwg.	Figs. Drwg.
<input type="checkbox"/> <b>TERMINAL DISCLAIMER</b>		PREPARED FOR ISSUE	Application Examiner	
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